Search Notes					

Application No.	Applicant(s)	
10/608,883	AVANZINO ET AL.	
Examin r	Art Unit	
Stephen W. Smoot	2813	

SEARCHED				
Class	Subclass	Date	Examiner	
257	751	5/25/2004	sws	
257	752	5/25/2004	sws	
257	759	5/25/2004	sws	
257	760	5/25/2004	sws	
257	762	5/25/2004	sws	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
-					
	1		1		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Considered all citations from parent applications.	5/25/2004	\$.10.5 sws		
Key Words: Damascene Structure - Inlaid, Copper, Electroplated, Seed Layer;	5/25/2004	S.W.S sws		
Interlayer Dielectric - SiCOH, MSQ; Insulating Barrier - SiCH.	5/25/2004	I.W.L sws		
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	5/25/2004	J.W.J.		